Experimental Verification of a Timing Measurement Circuit With Self-Calibration

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Supported by STARC

Outline

- Research Background
- TDC Circuit and Problems
- Histogram Method Self-Calibration
- Analog FPGA Implementation
- Measurement Results
- Conclusions

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<u>Research Background</u>

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Research Background



A Time-to-Digital Converter (TDC) provides a digital output proportional to the time between two clock transitions.

The TDC is a key component in time-domain analog circuits,

(e.g. Sensor Interfaces, All-Digital PLLs, ADCs, ...)

Validate TDC linearity self-calibration with histogram method

All-digital implementation



Suitable for fine CMOS

Experimentally validate design with FPGA

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Flash-type TDC



Delay Cell Variation Inside TDC Circuit



Random Variation among Delay Cells

Delay *τ* variation
Relative variation
TDC nonlinearity
Absolute (average value) variation
TDC input range & time resolution

• Focus on Relative variation here.

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Research Objective (revisited)

• TDC linearity self-calibration with histogram



• Analog FPGA(PSoC) implementation, evaluation

TDC with Self-Calibration



Normal Operation Mode



Self-Calibration Mode



Self-Calibration

Self-calibration mode

START, STOP signals are NOT synchronized



Histogram data in all bins will be equal, after collection of a sufficiently large number of data, if the TDC has perfect linearity

Principle of TDC Linearity Calibration

• START (ring oscillator) and STOP signals are asynchronous.



- Probability of digital code for large delay is high.
- Probability of digital code for small delay is low.

Self-Calibration



Principle of Self-Calibration



Simulation Result of Self-Calibration



Sampling points 28,848,432

 $\tau_1 = 60 \sim 69 \, ps$ $\tau_2 = 10 ns$

Histogram for each bin is the same when the TDC is linear.

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Implementation of TDC with Self-Calibration

Programmable System-on-Chip (PSoC) 5LP and external components



TDC Control Circuit in PSoC



START, STOP Generation for TDC Evaluation





TDC and Ring Oscillator Circuit



Encoder Circuit

Thermometer code to binary code



Data Processing Software

- C # program
- Data were transferred via USB to a PC and processed there.

Self Correction TDC (実行中) - Microsoft	Visual Studio Express 2012	for Windows Desktop (管理者)			クイック起動 (Ctrl+Q) 👂 – 🗗 🗙
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Histogram in Calibration Mode



- Total number of data: 40934
- Average number of data for each bin: 1700

TDC Measurement Without Calibration



Actual Delay Data by Direct Measurement



Delay Cell

Correlation Between Histogram and Delay



TDC Characteristics Before and After Calibration



Time difference between two clock rising edges

INL Before and After Calibration (1)



INL Before and After Calibration (2)









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Conclusion

- A TDC with self-calibration was implemented using an analog FPGA.
- Measurement results showed
 - Linearity improved by self-calibration.
- All-digital implementation is possible.
 - Suitable for fine CMOS

BOST for timing signal test

Altera FPGA (Full digital Implementation)

TDC with histogram method self-calibration

Delay cell array was implemented with a CMOS inverter chain.



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INL Before and After Self-Calibration

Measurement results



19th IEEE IMS3TW, Porto Alegre, Brazil

Sept. 17, 2014

Thank you for kind attention

Time continues indefinitely.





Kobayashi Laboratory



We are analog design & test researchers, but we appreciate digital technology.



19th Annual International Mixed-Signals, Sensors, and Systems Test Workshop



September 17-19, 2014 - Porto Alegre, Brazil